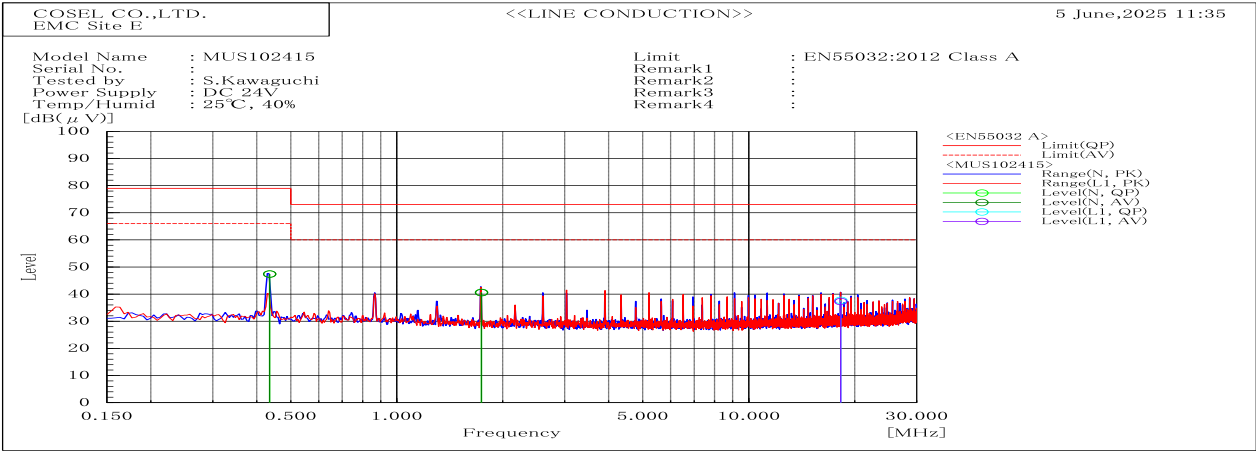
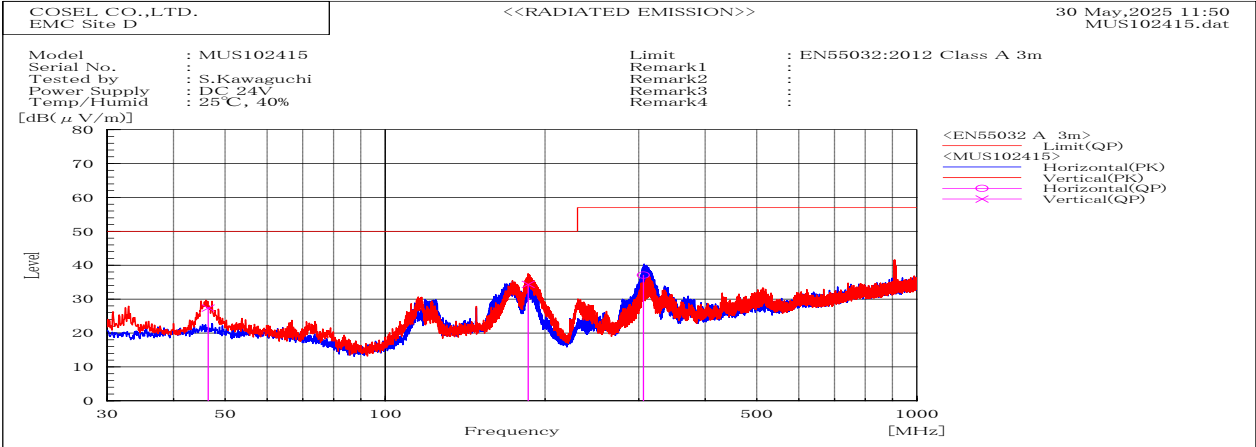


DATA SHEET		Date	05-Jun-25
Model	MUS102415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



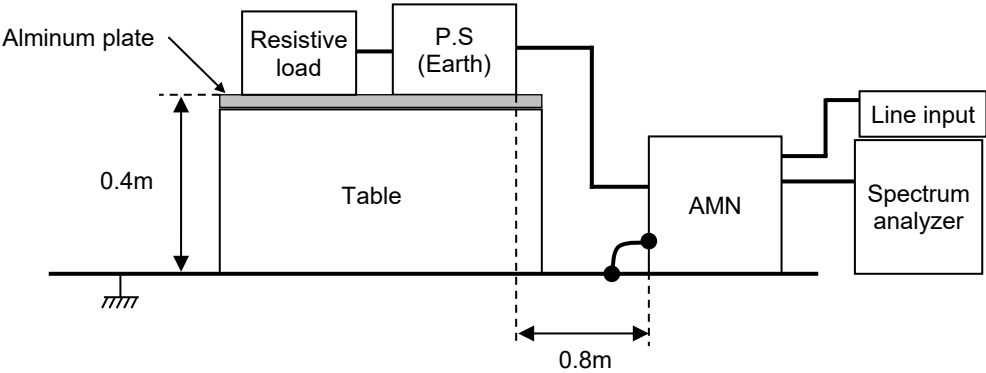
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
18.266	L1	37.7	37.3	73	60	35.3	22.7	Pass	
0.435	N	47.4	47.4	79	66	31.6	18.6	Pass	
1.74	N	40.6	40.5	73	60	32.4	19.5	Pass	



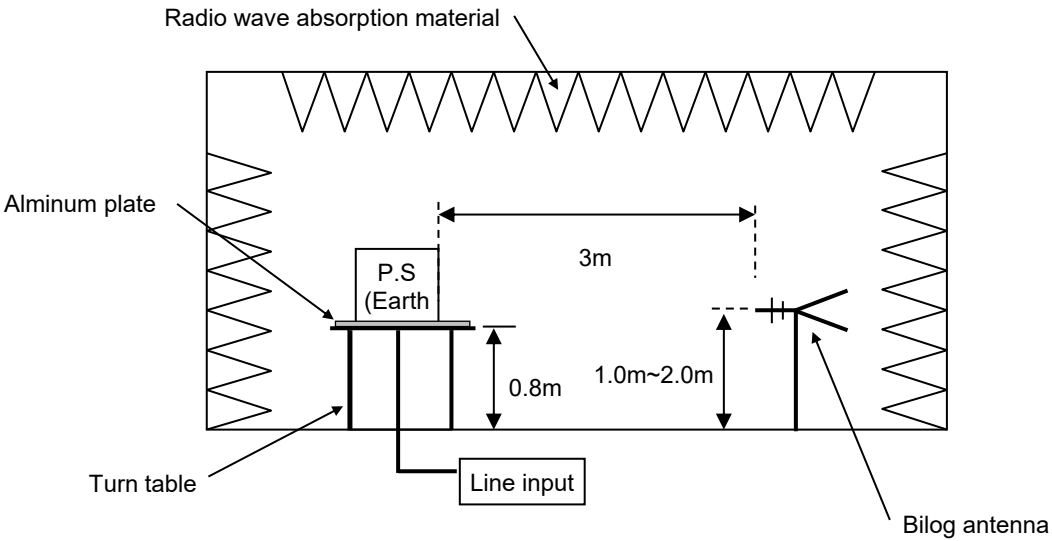
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
185.812	V	Stable	34.3	50	15.7	Pass	100	0	
46.469	V	Stable	27.4	50	22.6	Pass	100	22.4	
306.067	H	Stable	37.1	57	19.9	Pass	111.8	242.5	

DATA SHEET		Date	05-Jun-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

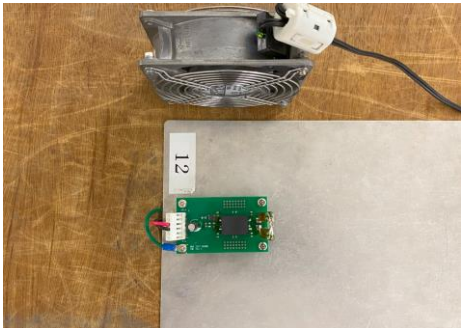
Test : EMI
 Model Name: MUS10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

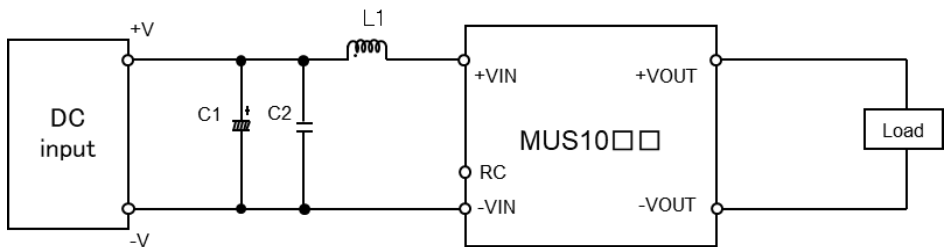


Fig.1 MUS10□□ Testing circuitry

C1 :	MUS1005□	25V 1500 μ F	Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MUS1012□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS1024□	—	
	MUS1048□	—	
C2 :	MUS1005□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1012□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUS1024□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUS1048□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1005□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUS1012□	3500mA 4.7 μ H	Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING)
	MUS1024□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)
	MUS1048□	1100mA 47 μ H	Inductor(LQH5BPN470M38 MURATA MANUFACTURING)